

Notice of References Cited	Application/Control No. 10/731,482	Applicant(s)/Patent Under Reexamination LEE, JOON HYEON	
	Examiner Lynne A. Gurley	Art Unit 2812	Page 1 of 1


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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	 LYNNE A. GURLEY PRIMARY PATENT EXAMINER TG 2800, AU 2812
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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